

## Single 8-Channel/Differential 4-Channel CMOS Analog Multiplexers

June 1994

### Features

- This Circuit Is Processed in Accordance to MIL-STD-883 and is Fully Conformant Under the Provisions of Paragraph 1.2.1.
- ON-Resistance 100Ω Maximum (+25°C)
- Low Power Consumption ( $P_D < 11\text{mW}$ )
- Fast Switching Action
  - $t_{\text{TRANS}} < 250\text{ns}$
  - $t_{\text{ON/OFF(EN)}} < 150\text{ns}$
- Low Charge Injection
- Upgrade from DG508A/DG509A
- TTL, CMOS Compatible
- Single or Split Supply Operation

### Applications

- Data Acquisition Systems
- Audio Switching Systems
- Automatic Testers
- Hi-Rel Systems
- Sample and Hold Circuits
- Communication Systems
- Analog Selector Switch

### Description

The DG408/883 Single 8-Channel and DG409/883 Differential 4-Channel monolithic CMOS analog multiplexers are drop-in replacements for the popular DG508A and DG509A series devices. They each include an array of eight analog switches, a TTL/CMOS compatible digital decode circuit for channel selection, a voltage reference for logic thresholds and an ENABLE input for device selection when several multiplexers are present.

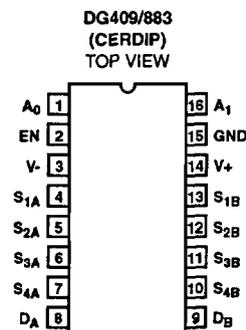
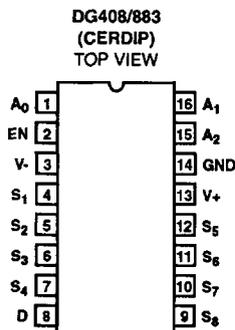
The DG408/883 and DG409/883 feature lower signal ON resistance ( $< 100\Omega$ ) and faster switch transition time ( $t_{\text{TRANS}} < 250\text{ns}$ ) compared to the DG508A or DG509A. Charge injection has been reduced, simplifying sample and hold applications. The improvements in the DG408/883 series are made possible by using a high-voltage silicon-gate process. An epitaxial layer prevents the latch-up associated with older CMOS technologies. Power supplies may be single-ended from +5V to +34V, or split from  $\pm 5\text{V}$  to  $\pm 20\text{V}$ .

The analog switches are bilateral, equally matched for AC or bidirectional signals. The ON resistance variation with analog signals is quite low over a  $\pm 5\text{V}$  analog input range.

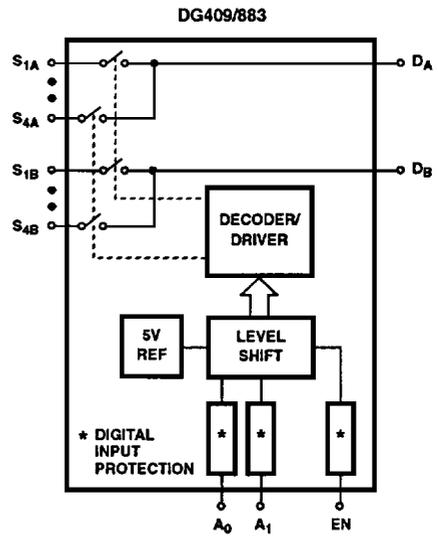
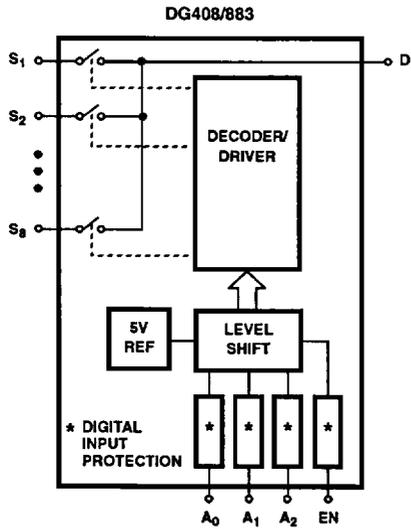
### Ordering Information

PART NUMBER	TEMPERATURE RANGE	PACKAGE
DG408AK/883	-55°C to +125°C	16 Lead CerDIP
DG409AK/883	-55°C to +125°C	16 Lead CerDIP

### Pinouts



Functional Block Diagrams



**DG408/883, DG409/883**

**Pin Description - (DG408/883)**

PIN	SYMBOL	DESCRIPTION
1	A <sub>0</sub>	Logic Decode Input (Bit 0, LSB)
2	EN	Enable Input
3	V-	Negative Power Supply Terminal
4	S <sub>1</sub>	Source (Input) for Channel 1
5	S <sub>2</sub>	Source (Input) for Channel 2
6	S <sub>3</sub>	Source (Input) for Channel 3
7	S <sub>4</sub>	Source (Input) for Channel 4
8	D	Drain (Output)
9	S <sub>8</sub>	Source (Input) for Channel 8
10	S <sub>7</sub>	Source (Input) for Channel 7
11	S <sub>6</sub>	Source (Input) for Channel 6
12	S <sub>5</sub>	Source (Input) for Channel 5
13	V+	Positive Power Supply Terminal (Substrate)
14	GND	Ground Terminal (Logic Common)
15	A <sub>2</sub>	Logic Decode Input (Bit 2, MSB)
16	A <sub>1</sub>	Logic Decode Input (Bit 1)

**Pin Description - (DG409/883)**

PIN	SYMBOL	DESCRIPTION
1	A <sub>0</sub>	Logic Decode Input (Bit 0, LSB)
2	EN	Enable Input
3	V-	NegAtive Power Supply Terminal
4	S <sub>1A</sub>	Source (Input) for Channel 1A
5	S <sub>2A</sub>	Source (Input) for Channel 2A
6	S <sub>3A</sub>	Source (Input) for Channel 3A
7	S <sub>4A</sub>	Source (Input) for Channel 4A
8	D <sub>A</sub>	Drain A (Output A)
9	D <sub>B</sub>	Drain B (Output B)
10	S <sub>4B</sub>	Source (Input) for Channel 4B
11	S <sub>3B</sub>	Source (Input) for Channel 3B
12	S <sub>2B</sub>	Source (Input) for Channel 2B
13	S <sub>1B</sub>	Source (Input) for Channel 1B
14	V+	Positive Power Supply Terminal
15	GND	Ground Terminal (Logic Common)
16	A <sub>1</sub>	Logic Decode Input (Bit 1, MSB))

**TRUTH TABLE DG408/883**

A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	EN	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

**TRUTH TABLE DG409/883**

A <sub>1</sub>	A <sub>0</sub>	EN	ON SWITCH
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

**NOTES:**

1. V<sub>AH</sub> Logic "1" ≥2.4V.
2. V<sub>AL</sub> Logic "0" ≤0.8V.

## Specifications DG408/883, DG409/883

### Absolute Maximum Ratings

V+ to V-	.....+44.0V
GND to V-	..... 25V
Digital Inputs (Note 1)	..... (V-) -2V to (V+) + 2V or 20mA, Whichever Occurs First
Current (Any Terminal, Except S or D)	.....30mA
Continuous Current, S or D	.....20mA
Peak Current, S or D (Pulsed 1ms, 10% Duty Cycle)	.....40mA
Storage Temperature Range	..... -65°C to +125°C
Lead Temperature (Soldering, 10s)	..... +300°C

### Thermal Information

Thermal Resistance	$\theta_{JA}$	$\theta_{JC}$
CerDIP Package	70°C/W	20°C/W
Operating Temperature	-55°C to +125°C	
Junction Temperature	+175°C	

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

**TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS**

Device Tested at:  $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ , V+ = +15V, V- = -15V, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Drain-Source ON Resistance	$r_{DS(ON)}$	$V_D = \pm 10V$ , $V_{AL} = 0.8V$ , $V_{AH} = 2.4V$ , $I_S = -10mA$ , Sequence Each Switch On	1, 3	+25°C, -55°C	-	100	$\Omega$
			2	+125°C	-	125	$\Omega$
Difference In Drain-Source ON Resistance Between Channels	$\Delta r_{DS(ON)}$	$V_D = \pm 10V$ , $V_{AL} = 0.8V$ , $V_{AH} = 2.4V$ , $I_S = -10mA$ , (Note 2)	1	+25°C	-	15	$\Omega$
Source OFF Leakage Current	$I_{S(OFF)}$	$V_S = \pm 10V$ , $V_D = \mp 10V$ , $V_{EN} = 0V$	1	+25°C	-0.5	+0.5	nA
			2	+125°C	-50	+50	nA
Drain OFF Leakage Current  DG408/883  DG409/883	$I_{D(OFF)}$	$V_S = \pm 10V$ , $V_D = \mp 10V$ , $V_{EN} = 0V$	1	+25°C	-1	+1	nA
			2	+125°C	-200	+200	nA
			1	+25°C	-1	+1	nA
			2	+125°C	-100	+100	nA
Drain ON Leakage Current  DG408/883  DG409/883	$I_{D(ON)}$	$V_S = V_D = \pm 10V$ , $V_{AL} = 0.8V$ , $V_{AH} = 2.4V$ , $V_{EN} = 2.4V$ , Sequence Each Switch On	1	+25°C	-1	+1	nA
			2	+125°C	-200	+200	nA
			1	+25°C	-1	+1	nA
			2	+125°C	-150	+150	nA
Logic Input Current, Input Voltage High	$I_{AH}$	$V_{EN} = 0.8V$ , $V_A = 2.4V$	1, 2, 3	+25°C, +125°C, -55°C	-10	+10	$\mu A$
		$V_{EN} = 0.8V$ , $V_A = 15V$			-10	+10	$\mu A$
Logic Input Current, Input Voltage Low	$I_{AL}$	$V_{EN} = 0V$ , $V_A = 0V$	1, 2, 3	+25°C, +125°C, -55°C	-10	+10	$\mu A$
		$V_{EN} = 2.4V$ , $V_A = 0V$			-10	+10	$\mu A$
Positive Supply Current Standby	$I_{+(SB)}$	$V_{EN} = 0V$ , $V_A = 0V$	1, 2, 3	+25°C, +125°C, -55°C	-	75	$\mu A$

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CMOS ANALOG MULTIPLEXERS

## Specifications DG408/883, DG409/883

**TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)**

Device Tested at:  $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ ,  $V_+ = +15\text{V}$ ,  $V_- = -15\text{V}$ , Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Negative Supply Current Standby	$I_{(SB)}$	$V_{EN} = 0\text{V}$ , $V_A = 0\text{V}$	1, 2, 3	+25°C, +125°C, -55°C	-75	-	μA
Positive Supply Current	I+	$V_{EN} = 2.4\text{V}$ , $V_A = 0\text{V}$	1, 3	+25°C, -55°C	-	0.5	mA
			2	+125°C	-	2	mA
Negative Supply Current	I-	$V_{EN} = 2.4\text{V}$ , $V_A = 0\text{V}$	1, 2, 3	+25°C, +125°C, -55°C	-0.5	-	mA

**TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS**

Device Tested at:  $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ ,  $V_+ = +15\text{V}$ ,  $V_- = -15\text{V}$ , Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Switching Time of Multiplexer	$t_{TRANS}$		9, 10, 11	+25°C, +125°C, -55°C	-	250	ns
Enable Turn ON Time	$t_{ON(EN)}$		9, 11	+25°C, -55°C	-	150	ns
			10	+125°C	-	225	ns
Enable Turn OFF Time	$t_{OFF(EN)}$		9, 10, 11	+25°C, +125°C, -55°C	-	150	ns
Break-Before-Make Interval	$t_{OPEN}$		9	+25°C	10	-	ns

**TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS**

Table 3 Intentionally Left Blank.

**TABLE 4. ELECTRICAL TEST REQUIREMENTS**

MIL-STD-883 TEST REQUIREMENTS	SUBGROUPS (SEE TABLES 1 AND 2)
Interim Electrical Parameters (Pre Burn-In)	1
Final Electrical Test Parameters	1 (Note 3), 2, 3, 9, 10, 11
Group A Test Requirements	1, 2, 3, 9, 10, 11
Groups C and D Endpoints	1

**NOTES:**

1. Signals on  $S_X$ ,  $D_X$ , or  $IN_X$  exceeding  $V_+$  or  $V_-$  will be clamped by internal diodes. Limit forward diode current to maximum current ratings.
2.  $\Delta r_{DS(ON)} = r_{DS(ON)} \text{ MAX} - r_{DS(ON)} \text{ MIN}$ .
3. PDA applies to Subgroup 1 only.

**Die Characteristics**

**DIE DIMENSIONS:**

1800 $\mu$ m x 3320 $\mu$ m x 485  $\pm$  25 $\mu$ m

**METALLIZATION:**

Type: SiAl

Thickness: 12k $\text{\AA}$   $\pm$  1k $\text{\AA}$

**GLASSIVATION:**

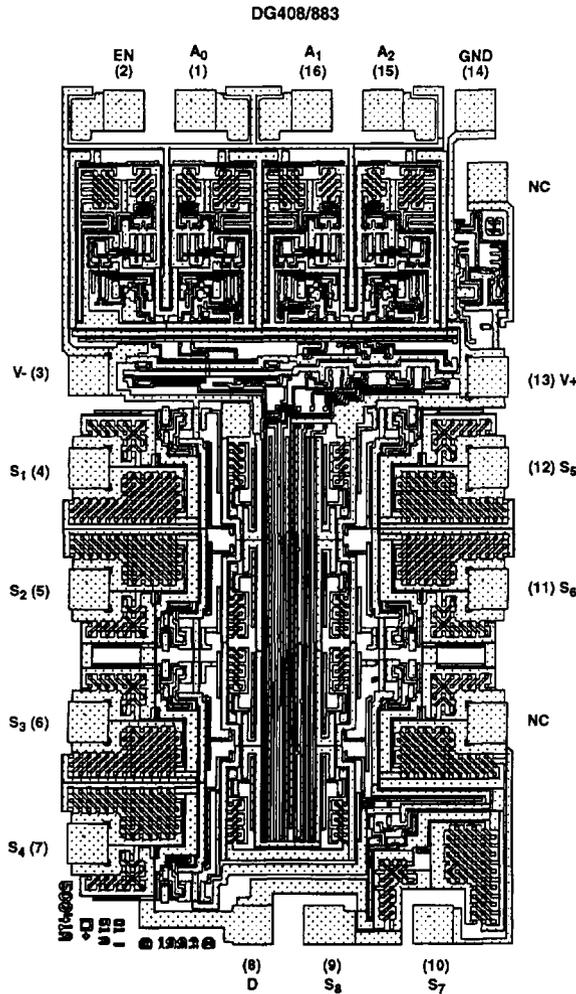
Type: Nitride

Thickness: 8k $\text{\AA}$   $\pm$  1k $\text{\AA}$

**WORST CASE CURRENT DENSITY:**

9.1 x 10<sup>4</sup> A/cm<sup>2</sup>

**Metallization Mask Layout**



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CMOS ANALOG  
MULTIPLIXERS

**Die Characteristics**

**DIE DIMENSIONS:**

1800 $\mu$ m x 3320 $\mu$ m x 485  $\pm$  25 $\mu$ m

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Type: SiAl  
 Thickness: 12k $\text{Å}$   $\pm$  1k $\text{Å}$

**GLASSIVATION:**

Type: Nitride  
 Thickness: 8k $\text{Å}$   $\pm$  1k $\text{Å}$

**WORST CASE CURRENT DENSITY:**

9.1 x 10<sup>4</sup> A/cm<sup>2</sup>

**Metallization Mask Layout**

